

Notice of References Cited	Application/Control No. 10/724,193	Applicant(s)/Patent Under Reexamination SUNTER, STEPHEN K.	
	Examiner Toan M. Le	Art Unit 2863	Page 1 of 1

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	C	US-5,481,471	01-1996	Naglestad et al.	716/4
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	W	Borkowska et al., Investigations of Mixed-Signal Circuits Equipped with Innovative Test Bus, 1999 IEEE, Pages 1553-1557
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.